AMENDMENTS TO THE CLAIMS

The listing of claims will replace all prior versions and listings of claims in the application:

Listing of Claims:

1. **(Original)** A method of testing an optical subassembly ("OSA") of an optoelectronic device, comprising:

providing a tester apparatus comprising:

a printed circuit board having a test circuit formed thereon, and

an electrical interface disposed in electrical communication with the test circuit;

forming a temporary electrical connection between a secondary circuit and the electrical interface of the tester apparatus;

transmitting a data stream through the OSA; and

evaluating the data stream.

2. **(Original)** The method as recited in claim 1, wherein forming a temporary electrical connection between a secondary circuit and the electrical interface of the tester apparatus further comprises forming an electrical connection between the OSA and the secondary circuit.

3. **(Original)** The method as recited in claim 1, wherein the optical subassembly is one of a transmitter optical subassembly ("TOSA") and a receiver optical subassembly ("ROSA").

4. **(Original)** The method as recited in claim 1, wherein the secondary circuit comprises a flexible circuit.

5. **Cancelled**

6. **(Original)** The method as recited in claim 1, wherein the optical subassembly is a transmitter optical subassembly (TOSA) wherein transmitting a data stream through the TOSA comprises sending a data stream in the form of an input electrical signal from the test circuit to the TOSA, wherein the TOSA outputs a corresponding optical signal.

7. **(Original)** The method as recited in claim 6, wherein evaluating the data stream further comprises analyzing the optical signal from the TOSA using an analyzer.

8. **(Original)** The method as recited in claim 1, further comprising transmitting the results of the evaluation to a computer.

9. **(Original)** The method as recited in claim 6, wherein evaluating the data stream comprises:

converting the optical signal from the TOSA back to an output electrical signal, and

comparing the input electrical signal with the output electrical signal.

10. **(Original)** The method as recited in claim 1, wherein the optical subassembly is a receiver optical subassembly (ROSA) wherein transmitting a data stream through the ROSA comprises sending a data stream in the form of an input optical signal through the ROSA, wherein the ROSA outputs a corresponding data stream in the form of an electrical signal.

11. **(Original)** The method as recited in claim 10, wherein evaluating the data stream further comprising transmitting the electrical signal from the secondary circuit to the test circuit.

12. **(Original)** The method as recited in claim 11, wherein evaluating the data stream further comprises transmitting the electrical signal from the test circuit to a computer.

13. **(Original)** An optical subassembly testing apparatus configured to evaluate an optical subassembly before the optical subassembly is connected to electrical components, the apparatus comprising:

a base member;

a test circuit disposed on the base member;

an electrical interface disposed in electrical communication with the test circuit, the electrical interface configured to be temporarily connected to the optical subassembly; and

means for temporarily placing the optical subassembly in electrical connection with the electrical interface.

14. **(Original)** The apparatus as recited in claim 13, wherein the means for temporarily placing the optical subassembly in temporary electrical connection with the electrical interface comprises a clamping assembly pivotably mounted to the base member.

15. **(Currently Amended)** The apparatus as recited in claim [[13]] 14, wherein the clamping assembly has a plurality of pivot points enabling the clamping assembly to engage the optical subassembly at the electrical interface with at least a connecting force and a locking force, wherein the locking force is greater than the connecting force.

16. **(Original)** The apparatus as recited in claim 13, wherein the means for temporarily placing the optical subassembly in temporary electrical connection with the electrical interface comprises a clamping assembly slidably mounted to the base member.

17. **(Original)** The apparatus as recited in claim 13, wherein the means for temporarily placing the optical subassembly in temporary electrical connection with the electrical interface comprises a clamping assembly disposed above the electrical interface and configured to engage the electrical interface in a press-fit configuration.

18. **(Original)** The apparatus as recited in claim 13, further comprising an analyzer configured to be temporarily connected to the optical subassembly.

19. **(Original)** The apparatus as recited in claim 18, further comprising a computer connected to the test circuit and to the analyzer.

20. **(Original)** The apparatus as recited in claim 18, wherein the analyzer is a bit error rate tester and an optical receiver.

21. **(Original)** The apparatus as recited in claim 18, wherein the analyzer is a bit error rate tester and an optical transmitter.

22. **(Original)** The apparatus as recited in claim 13, further comprising an optical pattern generator configured to be temporarily connected to the optical subassembly.

23. **(Original)** The apparatus as recited in claim 22, further comprising a computer connected to the test circuit and the optical pattern generator.

24. **(Original)** The apparatus as recited in claim 13, wherein the optical subassembly is one of a transmitter optical subassembly ("TOSA") and a receiver optical assembly ("ROSA").

25. **(Original)** An optical subassembly testing apparatus configured to evaluate an optical subassembly before the optical subassembly is connected to electrical components, the apparatus comprising:

a base member;

a test circuit disposed on the base member;

an electrical interface disposed in electrical communication with the test circuit, the electrical interface configured to be temporarily connected to the optical subassembly; and

a clamping assembly pivotably mounted to the base member, the clamping assembly configured for temporarily placing the optical subassembly in temporary electrical connection with the electrical interface.

26. **(Original)** The apparatus as recited in claim 25, wherein the clamping assembly has a plurality of pivot points enabling the clamping assembly to engage the optical subassembly at the electrical interface with at least a connecting force and a locking force, wherein the locking force is greater than the connecting force.

27. **(Original)** The apparatus as recited in claim 25, further comprising an analyzer configured to be temporarily connected to the optical subassembly.

28. **(Original)** The apparatus as recited in claim 27, further comprising a computer connected to the test circuit and to the analyzer.

29. **(Original)** The apparatus as recited in claim 27, wherein the analyzer is a bit error rate tester and an optical receiver.

30. **(Original)** The apparatus as recited in claim 27, wherein the analyzer is a bit error rate tester and an optical transmitter.

31. **(Original)** The apparatus as recited in claim 25, further comprising an optical pattern generator configured to be temporarily connected to the optical subassembly.

32. **(Original)** The apparatus as recited in claim 31, further comprising a computer connected to the test circuit and the optical pattern generator.